



# Agilent Technologies

Innovating the HP Way

## 1100 Series Multiple Wavelength Detector (MWD) Dark Current Test Procedure Using the Hand-Held Control Module

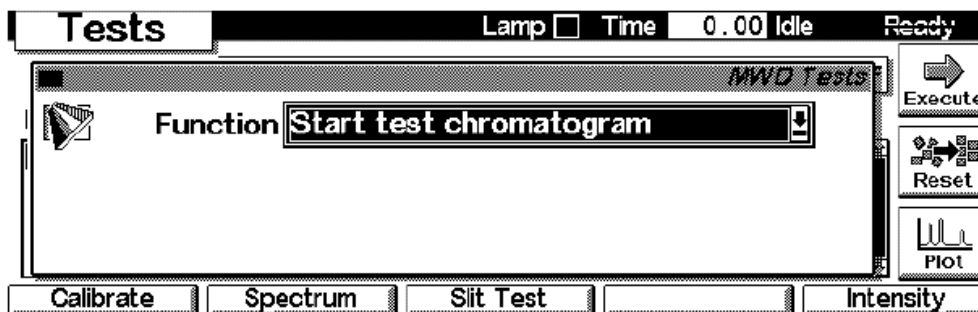
### Troubleshooting the Detector

1. Select the Tests button [F3] in the System screen.
2. Select the Detector from the menu.
3. Press the Enter key.
4. Select the Dark Current Test.

### Diagnostics and Tests

#### Tests screen

Use the **Esc** key to receive **Views** on the F5 key. Choose **System** from the pull-down menu. Use the F3 key (**Tests**) to select the MWD. Several tests are available to test the Agilent 1100 MWD. Additional test are listed in the function box. Refer to "Troubleshooting and Test Functions" on page 49 for more information on the tests.



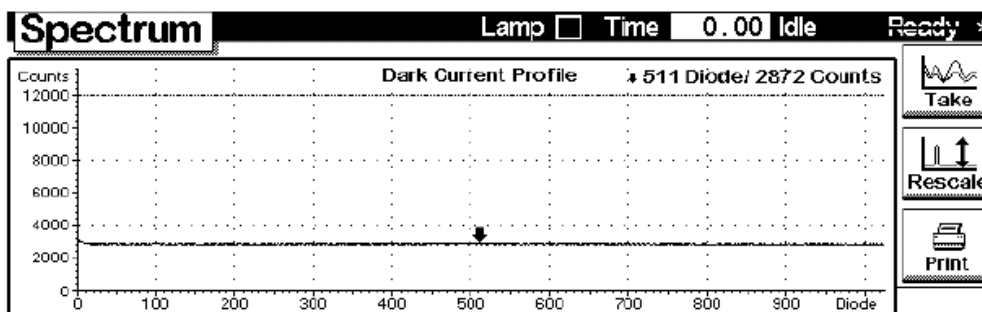
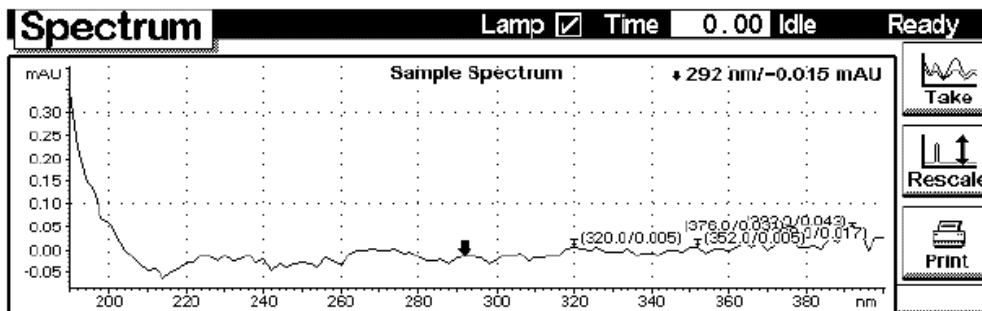
The selection of tests depends on the revision of the hand-held control module. For information about each test, see the *Reference Manual* for the Agilent 1100 detectors.

**NOTE** The full test capability is only available from the LC ChemStation.

This document is believed to be accurate and up-to-date. However, Agilent Technologies, Inc. cannot assume responsibility for the use of this material. The information contained herein is intended for use by informed individuals who can and must determine its fitness for their purpose.

**Sample, Holmium and  
Dark Current  
Spectrum**

Use the F2 key (**Spectrum**) to take a spectrum (sample, dark current or holmium). Use the Left/Right arrow to move the cursor within the spectrum to find the wavelength of interest.



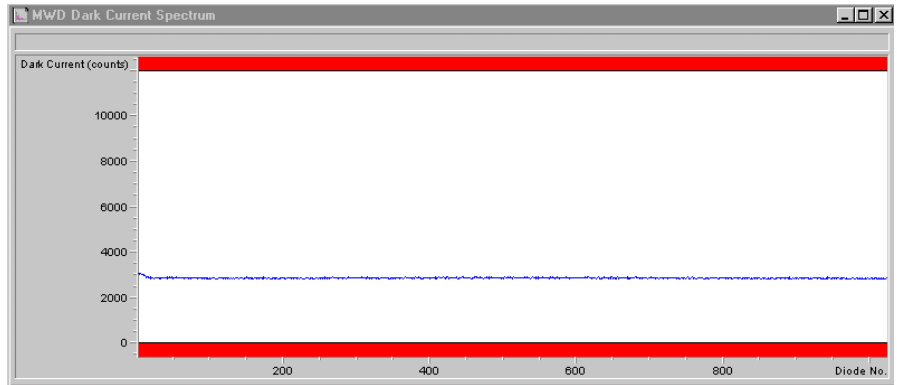
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## Dark-Current Test

The dark-current test measures the leakage current from each diode. The test is used to check for leaking diodes which may cause non-linearity at specific wavelengths. During the test, the slit assembly moves to the dark position, cutting off all light falling onto the diode array. Next, the leakage current from each diode is measured, and displayed graphically (see Figure 26). The leakage current (represented in *counts*) for each diode should fall within the limits (red bands) shown in the plot (see Figure 26).

**Figure 26**

### Dark-Current Test



## Dark-Current Test Evaluation

**Figure 27**

### Dark-Current Test Results

	Limits	Measured	Result
Date: 17.03.99; Time: 10:44:53			
Dark current maximum value	<= 12000 cts	3080 cts	Passed
Dark current minimum value	> 0 cts	2801 cts	Passed

### Test Failed

*Probable Causes*  
*Suggested Actions*

- Defective optical unit.
- Exchange the optical unit.